

ESREF 2010, the 21st European Symposium on Reliability of Electron Devices will take place in Gaeta and Monte Cassino Abbey (Italy) from 11th to 15th October 2010.

This international symposium continues to focus on recent developments and future directions in Quality and Reliability Management of materials, devices and circuits for micro, nano, and optoelectronics. It provides a European forum for developing all aspects of reliability management and innovative analysis techniques for present and future electronic applications.

LOCATION OF THE CONFERENCE (143 km from the Fiumicino international airport of Rome and 105 km from Capodichino international airport of Naples):

SUMMIT HOTEL
Via Flacca, Km 23
04024 GAETA (LT) – Italy

AN INVITATION TO EXHIBITORS

We cordially invite your company to exhibit at ESREF 2010.

The conference will concentrate on two main areas of interest in electronics concerning designers, manufacturers and users:

- Strategy for Quality and Reliability Assessment during Product Development and Life Cycle.

- Advanced Analysis Techniques for Technologies and Product Evaluation.

About 160 technical papers has been submitted and reasonably 80% of them will be presented at the Conference.

EQUIPMENT EXHIBITION

Large exhibit rooms will give the opportunity to key-vendors to represent the core business area in these fields.

There is time in the program each day for participants to visit the exhibits, with all coffee breaks in the exhibit areas to encourage physicians to meet with you to discuss your products and services.

For your convenience you can opt between two different locations.

For further information concerning the equipment exhibition, please contact:

Carmine Abbate
esref2010@unicas.it

STEERING COMMITTEE

X. AYMERICH	- University of Barcelona (Spain)
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PROGRAMME COMMITTEE

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G. MENEGHESSO - University of Padova (I)

Conference Scientific Support:

G. CURRO' - STMicroelectronics, Catania (I)

M. VANZI - University of Cagliari (I)

F. SVELTO - ASI, Roma (I)

Industrial Exhibition:

C. ABBATE, A. PORZIO - University of Cassino (I)

Journal edition chairs:

G. BUSATTO - University of Cassino (I)

F. IANNUZZO - University of Cassino (I)

TECHNICAL SUBCOMMITTEE CHAIRS

Reliability of Photovoltaic and Organic devices: Thin Film, concentration, OLED, TFT (*HOT topic*)

Carlos ALGORA (ETSIT, Spain)
Roberta CAMPESATO (CESI, Italy)

Quality and Reliability Techniques for Devices and Systems

Francesco SVELTO (ASI, Italy)
Christopher BAILEY (University of Greenwich, UK)

Characterisation of Failure Mechanisms: Hot carriers, high K, gate materials

Giuseppe CURRO' (STMicroelectronics, Italy)
Ninoslav D. STOJADINOVIC (University of Nis, Serbia)

Characterisation of Failure Mechanisms: low K, Cu Interconnects

Cora SALM (MESA+ Research Institute/ University of Twente, The Netherlands)
Cher Ming TAN (Nanyang Technological University, Singapore)

Characterisation of Failure Mechanisms: ESD, Latch-up

Gianluca BOSELLI (Texas Instruments, USA)
Gernot LANGGUTH (Infineon, Germany)

Advanced Failure analysis: Electron and Optical Beam Testing

Ralph HEIDERHOFF (Bergische Universität Wuppertal, Germany)
Paolo SPIRITO (University of Napoli, Italy)

Advanced Failure analysis: Other advanced characterisation techniques

Philippe PERDU (CNES, France)
Massimo VANZI (University of Cagliari, Italy)

Failures in Microwave, Wide Band-Gap and Photonic Devices

Nathalie LABAT (IMS, University of Bordeaux)
Roberto MENOZZI (University of Parma, Italy)

Packaging, Assemblies, Passive Components and MEMS

Fabio COCCETTI (Novamems/ LAAS-CNRS, France)
Augusto TAZZOLI (University of Padova, Italy)

Extreme environments: Power, Automotive and industrial applications

Mauro CIAPPA (ETH Zürich, Switzerland)
Eckhard WOLFGANG (Siemens, Germany)

Extreme environments: Aeronautic and spatial electronics

Jean-Luc LERAY (CEA, France)
Alessandro PACCAGNELLA (Università di Padova, Italy)

INVITED TALKS

A confirmed list of the invited talks is:

"How future automotive functional safety requirements will impact microprocessors design"

by Marco BELLOTTI – Engineering&Design Electrical Electronics department, Fiat Group Automobiles (Italy)

"MEMS technology integrated in the CMOS back-end"

by Roberto GADDI – Cavendish Kinetics (The Netherlands)

"Advanced Packaging yields to Higher Performance and Reliability in Power Electronics"

by Reinhold BAYERER – Infineon Technologies AG (Germany)

"Soft-Errors induced by terrestrial neutrons and natural alpha-particle emitters in advanced memory circuits at ground level"

by Jean-Luc AUTRAN – Aix-Marseille University, IM2NP-CNRS (France)

"High-k related reliability issues in advanced Non-Volatile Memories"

by Luca LARCHER – University of Modena and Reggio Emilia (Italy)

"Reliability of III-V concentrator solar cells"

by Carlos ALGORA – Solar Energy Institute, Polytechnic University of Madrid (Spain)

"Overview of the recent progress in high-k reliability, i.e. breakdown and PBTI, including results on fully-depleted devices."

by James H. STATHIS – IBM Research (NY, USA)

"Application of TEM Analysis and holography to GaN-based devices"

by David J. SMITH – Arizona State University, Tempe (AZ, USA)

More international leaders in the reliability field have given their availability for invited speeches. Please, check the website for updates.

Organisation Secretariat

Francesco VELARDI

UNIVERSITY OF CASSINO - ESREF 2010

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<http://www.esref2010.unicas.it>

<http://www.esref.org>

SOME NEIGHBOURING COMPANIES

Semikron Srl

Via Laurentina, Km 24,200

00040

Pomezia

(RM) Roma Italia

<http://www.semikron.com>

E.P. Elettronica Progetti s.r.l.

Via degli Oleandri 47

00040 Ariccia (RM) Italy

<http://www.elettronicaprogetti.com/>

Selcon Elettronica

via s.s 156Km 42.100 Sezze (LT)

<http://www.selconelettronica.it/>

Alenia Aeronautica

Via Campania 45, 00187 – Roma

<http://www.alenia-aeronautica.it/>

Telespazio

Roma – Headquarters

Via Tiburtina, 965 00156 Rome

<http://www.telespazio.com/>

Vitrociset SPA

Via Tiburtina, 1020

00156 ROMA (RM)

<http://www.vitrociset.it/>

Sky-Technology

via Adolfo Ravà, 124

00142 Roma (ITALY)

<http://www.skytechnology.it>

Stmicroelectronics Srl

Via Defeo Remo, Arzano, NA 80022

081 2381111

<http://www.st.com>

CALL FOR EXHIBITORS

21st EUROPEAN SYMPOSIUM ON RELIABILITY OF ELECTRON DEVICES, FAILURE PHYSICS AND ANALYSIS

Gaeta – Italy
11 - 15 October 2010



Organized by:



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of Cassino

and



with the technical co-sponsorship of :



Department of Automation,
Electromagnetism, Informa-
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